# 4V Drive Pch+SBD MOSFET us5u35

# ●Structure

Silicon P-channel MOSFET Schottky Barrier DIODE

#### Features

- 1) The US5U35 combines Pch MOSFET with a Schottky barrier diode in a TUMT5 package.
- 2) With fast switching.
- 3) Built-in schottky barrier diode has low forward voltage.

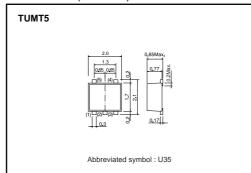
## Applications

Switching

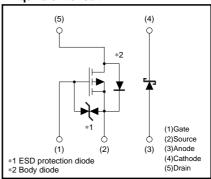
## Packaging specifications

	Package	Taping		
Type	Code	TR		
	Basic ordering unit (pieces)	3000		
US5U35		0		

## ●Dimensions (Unit: mm)



## ●Equivalent circuit



# ● Absolute maximum ratings (Ta=25°C)

## <MOSFET>

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Parameter	Symbol	Limits	Unit	
Drain-source voltage	V <sub>DSS</sub>	-45	V	
Gate-source voltage		V <sub>GSS</sub>	±20	V
Drain augrant	Continuous	ΙD	±0.7	А
Drain current	Pulsed	I <sub>DP</sub> *1	±2.8	А
Source current	Continuous	Is	-0.4	А
(Body diode)	Pulsed	I <sub>SP</sub> *1	-2.8	А
Channel temperature	Tch	150	°C	
Power dissipation	P <sub>D</sub> *3	0.7	W/ELEMENT	
<di></di>				
Repetitive peak reverse voltage		VRM	45	V
Reverse voltage		V <sub>R</sub>	40	V
Forward current	l <sub>F</sub>	100	mA	
Forward current surge peak		I <sub>FSM</sub> *2	1.0	А
Junction temperature	Tj	150	°C	
Power dissipation	P <sub>D</sub> *3	0.5	W / ELEMENT	
<mosfet and="" di=""></mosfet>				
Power dissipation	P <sub>D</sub> *3	1.0	W / TOTAL	
Range of storage tempera	Tstg	-55 to +150	°C	

<sup>\*1</sup> Pw≤10μs, Duty cycle≤1% \*2 60Hz•1cyc. \*3 Mounted on a ceramic board

# ●Electrical characteristics (Ta=25°C)

## <MOSFET>

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Gate-source leakage	Igss	_	_	±10	μΑ	Vgs=±20V, Vps=0V
Drain-source breakdown voltage	V(BR) DSS	-45	_	_	V	In=-1mA, Vgs=0V
Zero gate voltage drain current	IDSS	_	_	-1	μА	V <sub>DS</sub> =-45V, V <sub>GS</sub> =0V
Gate threshold voltage	VGS (th)	-1.0	_	-2.5	٧	V <sub>DS</sub> =-10V, I <sub>D</sub> =-1mA
Static drain-source on-state resistance	*	_	0.6	0.8	Ω	ID=-0.7A, VGS=-10V
	RDS (on)	_	0.9	1.3	Ω	ID=-0.7A, VGS=-4.5V
		_	1.0	1.4	Ω	ID=-0.35A, VGS=-4.0V
Forward transfer admittance	Y <sub>fs</sub>  *	0.6	-	_	S	Vps=-10V, Ip=-0.7A
Input capacitance	Ciss	_	120	_	pF	Vps=-10V
Output capacitance	Coss	_	14	_	pF	V <sub>G</sub> s=0V
Reverse transfer capacitance	Crss	_	11	_	pF	f=1MHz
Turn-on delay time	<b>t</b> d (on) *	_	6	_	ns	ID=-0.35A
Rise time	tr *	_	5	_	ns	VDD≒-25V
Turn-off delay time	td (off) *	_	17	_	ns	V <sub>GS</sub> =−10V R <sub>L</sub> ≒71Ω
Fall time	t <sub>f</sub> *	_	6	_	ns	R <sub>G</sub> =10Ω
Total gate charge	Qg	_	1.7	_	nC	V <sub>DD</sub> ≒–25V, V <sub>GS</sub> =–5V
Gate-source charge	Qgs	_	0.8	_	nC	ID=-0.7A
Gate-drain charge	Qgd	_	0.5	_	nC	$R_L = 36\Omega, R_G = 10\Omega$
* Pulsed						

<Body diode (source-drain)>

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Forward voltage	Vsp *	_	_	-1.2	V	Is=-0.7A, Vgs=0V
* Pulsed						

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Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Forward voltage	VF	_	_	0.55	V	I <sub>F</sub> =100mA
Reverse current	l <sub>R</sub>	_	_	30	μΑ	V <sub>R</sub> =10V



#### Electrical characteristic curves

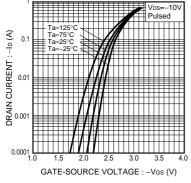


Fig.1 Typical Transfer Characteristics

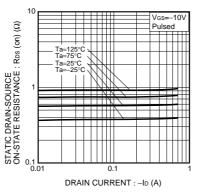


Fig.2 Static Drain-Source On-State Resistance vs. Drain Current(I)

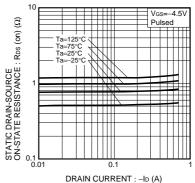


Fig.3 Static Drain-Source On-State Resistance vs. Drain Current(II)

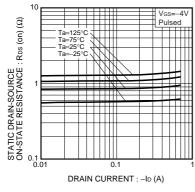


Fig.4 Static Drain-Source On-State Resistance vs. Drain Current(III)

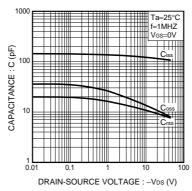


Fig.5 Typical Capacitance vs. Drain-Source Voltage

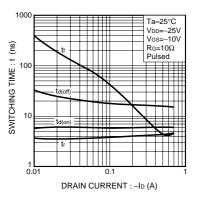


Fig.6 Switching Characteristics

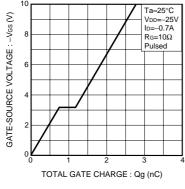


Fig.7 Dynamic Input Characteristics

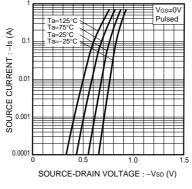


Fig.8 Source Current vs. Source-Drain Voltage

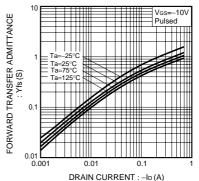


Fig.9 Forward Transfer Admittance vs.Drain Current

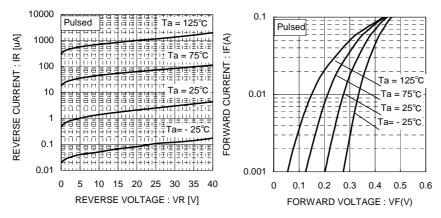


Fig.10 Reverse Current vs. Reverse Voltage

Fig.11 Forward Current vs. Forward Voltage

#### Notice

- 1. SBD has a large reverse leak current compared to other type of diode. Therefore; it would raise a junction temperature, and increase a reverse power loss. Further rise of inside temperature would cause a thermal runaway.
  This built-in SBD has low V<sub>F</sub> characteristics and therefore, higher leak current. Please consider enough the surrounding temperature, generating heat of MOSFET and the reverse current.
- 2. This product might cause chip aging and breakdown under the large electrified environment. Please consider to design ESD protection circuit.

## Measurement circuits

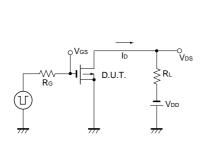


Fig.12 Switching Time Measurement Circuit

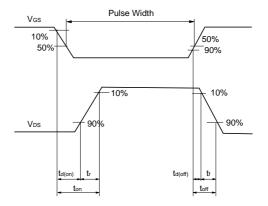


Fig.13 Switching Waveforms

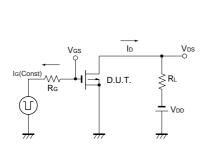


Fig.14 Gate Charge Measurement Circuit

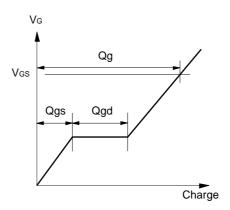


Fig.15 Gate Charge Waveforms

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ROHM CO., LTD. 21 Saiin Mizosaki-cho, Ukyo-ku, Kyoto 615-8585, Japan

pan TEL:+81-75-311-2121 FAX:+81-75-315-0172

